N-channel 100V  $12m\Omega$  standard level MOSFET in LFPAK

Rev. 04 — 23 February 2010

**Product data sheet** 

### 1. Product profile

#### 1.1 General description

Standard level N-channel MOSFET in LFPAK package qualified to 175 °C. This product is designed and qualified for use in a wide range of industrial, communications and domestic equipment.

#### 1.2 Features and benefits

- Advanced TrenchMOS provides low RDSon and low gate charge
- High efficiency gains in switching power converters

#### 1.3 Applications

- DC-to-DC converters
- Lithium-ion battery protection
- Load switching

### 1.4 Quick reference data

#### Table 1. Quick reference

- Improved mechanical and thermal characteristics
- LFPAK provides maximum power density in a Power SO8 package
- Motor control
- Server power supplies

Table 1.	Quick reference					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V <sub>DS</sub>	drain-source voltage	T <sub>j</sub> ≥ 25 °C; T <sub>j</sub> ≤ 175 °C	-	-	100	V
I <sub>D</sub>	drain current	T <sub>mb</sub> = 25 °C; see <u>Figure 1</u>	-	-	60	А
P <sub>tot</sub>	total power dissipation	$T_{mb} = 25 \text{ °C}; \text{ see } \frac{\text{Figure } 2}{\text{Figure } 2}$	-	-	130	W
Tj	junction temperature		-55	-	175	°C
Avalancl	he ruggedness					
E <sub>DS(AL)S</sub>	non-repetitive drain-source avalanche energy		-	-	170	mJ
Dynamic	characteristics					
$Q_{GD}$	gate-drain charge	$V_{GS} = 10 \text{ V}; \text{ I}_{D} = 45 \text{ A};$	-	19	-	nC
Q <sub>G(tot)</sub>	total gate charge	V <sub>DS</sub> = 50 V; see <u>Figure 14</u> and <u>15</u>	-	64	-	nC



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#### N-channel 100V 12mΩ standard level MOSFET in LFPAK

Table 1.         Quick reference continued						
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static c	haracteristics					
$R_{DSon}$	drain-source on-state resistance	$V_{GS}$ = 10 V; I <sub>D</sub> = 15 A; T <sub>j</sub> = 100 °C; see <u>Figure 12</u>	-	-	23	mΩ
		V <sub>GS</sub> = 10 V; I <sub>D</sub> = 15 A; T <sub>j</sub> = 25 °C; see <u>Figure 13</u>	-	10	12	mΩ

### 2. Pinning information

Table 2.	Pinning	information		
Pin	Symbol	Description	Simplified outline	Graphic symbol
1	S	source		
2	S	source	mb	
3	S	source		
4	G	gate	Q	
mb	D	mounting base; connected to drain		mbb076 S
			SOT669 (LFPAK)	

### 3. Ordering information

Table 3. Orde	Table 3. Ordering information					
Type number	Package					
	Name	Description	Version			
PSMN012-100Y	S LFPAK	plastic single-ended surface-mounted package (LFPAK); 4 leads	SOT669			

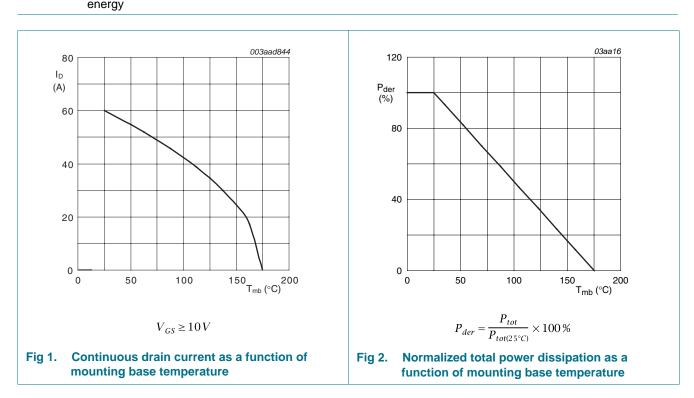
N-channel 100V 12m $\Omega$  standard level MOSFET in LFPAK

### 4. Limiting values

#### Table 4. Limiting values

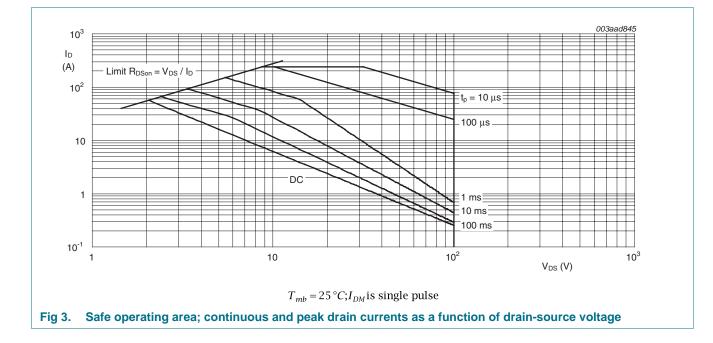
In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V <sub>DS</sub>	drain-source voltage	T <sub>j</sub> ≥ 25 °C; T <sub>j</sub> ≤ 175 °C	-	100	V
V <sub>DGR</sub>	drain-gate voltage	$T_j \ge 25 \text{ °C}; T_j \le 175 \text{ °C}; R_{GS} = 20 \text{ k}\Omega$	-	100	V
V <sub>GS</sub>	gate-source voltage		-20	20	V
I <sub>D</sub>	drain current	T <sub>mb</sub> = 100 °C; see <u>Figure 1</u>	-	43	А
		T <sub>mb</sub> = 25 °C; see <u>Figure 1</u>	-	60	А
I <sub>DM</sub>	peak drain current	$t_p \le 10 \ \mu s$ ; pulsed; $T_{mb} = 25 \ ^{\circ}C$ ; see Figure 3	-	242	А
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C; see <u>Figure 2</u>	-	130	W
T <sub>stg</sub>	storage temperature		-55	175	°C
Tj	junction temperature		-55	175	°C
T <sub>sld(M)</sub>	peak soldering temperature		-	260	°C
Source-dr	ain diode				
I <sub>S</sub>	source current	T <sub>mb</sub> = 25 °C	-	60	А
I <sub>SM</sub>	peak source current	$t_p \le 10 \ \mu s$ ; pulsed; $T_{mb} = 25 \ ^{\circ}C$	-	242	А
Avalanche	e ruggedness				
E <sub>DS(AL)S</sub>	non-repetitive drain-source avalanche energy	$V_{GS}$ = 10 V; $T_{j(init)}$ = 25 °C; $I_D$ = 60 A; $V_{sup}$ $\leq$ 100 V; $R_{GS}$ = 50 $\Omega;$ unclamped	-	170	mJ



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# **PSMN012-100YS**



δ

t<sub>p</sub> (s)

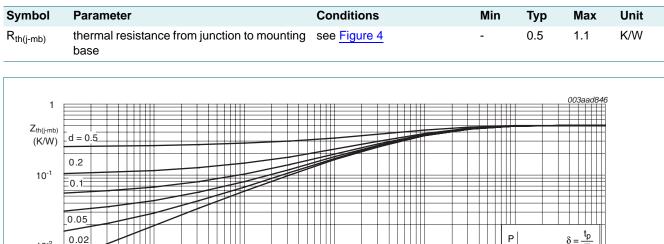
1

tp

10<sup>-1</sup>

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#### 5. **Thermal characteristics**



10<sup>-3</sup>

Transient thermal impedance from junction to mounting base as a function of pulse duration; typical

10<sup>-2</sup>

#### Table 5. **Thermal characteristics**

10<sup>-2</sup>

10<sup>-3</sup> 10<sup>-6</sup>

Fig 4.

~ single shot

values

10<sup>-5</sup>

10<sup>-4</sup>

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### 6. Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
•	racteristics					
V <sub>(BR)DSS</sub>	drain-source	I <sub>D</sub> = 0.25 mA; V <sub>GS</sub> = 0 V; T <sub>i</sub> = -55 °C	90	-	-	V
	breakdown voltage	$I_{\rm D} = 0.25 \text{ mA; } V_{\rm GS} = 0 \text{ V; } T_{\rm i} = 25 \text{ °C}$	100	-	-	V
V <sub>GS(th)</sub>	gate-source threshold voltage	$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 175 \text{ °C};$ see Figure 10	0.95	-	-	V
		$I_D$ = 1 mA; $V_{DS}$ = $V_{GS}$ ; $T_j$ = 25 °C; see Figure 11 and 10	2	3	4	V
		$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = -55 \text{ °C};$ see <u>Figure 10</u>	-	-	4.6	V
I <sub>DSS</sub>	drain leakage current	$V_{DS}$ = 100 V; $V_{GS}$ = 0 V; $T_j$ = 125 °C	-	-	100	μA
		V <sub>DS</sub> = 100 V; V <sub>GS</sub> = 0 V; T <sub>j</sub> = 25 °C	-	0.06	5	μA
I <sub>GSS</sub>	gate leakage current	$V_{GS}$ = 20 V; $V_{DS}$ = 0 V; $T_j$ = 25 °C	-	10	100	nA
		$V_{GS}$ = -20 V; $V_{DS}$ = 0 V; $T_j$ = 25 °C	-	10	100	nA
R <sub>DSon</sub>	drain-source on-state resistance	V <sub>GS</sub> = 10 V; I <sub>D</sub> = 15 A; T <sub>j</sub> = 100 °C; see <u>Figure 12</u>	-	-	23	mΩ
		V <sub>GS</sub> = 10 V; I <sub>D</sub> = 15 A; T <sub>j</sub> = 175 °C; see <u>Figure 12</u>	-	27	35.8	mΩ
		V <sub>GS</sub> = 10 V; I <sub>D</sub> = 15 A; T <sub>j</sub> = 25 °C; see <u>Figure 13</u>	-	10	12	mΩ
R <sub>G</sub>	internal gate resistance (AC)	f = 1 MHz	-	0.7	-	Ω
Dynamic o	haracteristics					
Q <sub>G(tot)</sub>	total gate charge	$I_D = 0 \text{ A}; \text{ V}_{DS} = 0 \text{ V}; \text{ V}_{GS} = 10 \text{ V}$	-	51	-	nC
		$I_D = 45 \text{ A}; V_{DS} = 50 \text{ V}; V_{GS} = 10 \text{ V};$	-	64	-	nC
Q <sub>GS</sub>	gate-source charge	see Figure 14 and 15	-	14.9	-	nC
Q <sub>GS(th)</sub>	pre-threshold gate-source charge	$I_D = 45 \text{ A}; V_{DS} = 50 \text{ V}; V_{GS} = 10 \text{ V};$ see Figure 14	-	10.2	-	nC
Q <sub>GS(th-pl)</sub>	post-threshold gate-source charge		-	4.7	-	nC
Q <sub>GD</sub>	gate-drain charge	$I_D = 45 \text{ A}; V_{DS} = 50 \text{ V}; V_{GS} = 10 \text{ V};$ see Figure 14 and 15	-	19	-	nC
V <sub>GS(pl)</sub>	gate-source plateau voltage	$V_{DS}$ = 50 V; see <u>Figure 14</u> and <u>15</u>	-	4.4	-	V
C <sub>iss</sub>	input capacitance	V <sub>DS</sub> = 50 V; V <sub>GS</sub> = 0 V; f = 1 MHz; T <sub>j</sub> = 25 °C;	-	3500	-	pF
C <sub>oss</sub>	output capacitance	see Figure 16	-	246	-	pF
C <sub>rss</sub>	reverse transfer capacitance		-	149	-	pF
t <sub>d(on)</sub>	turn-on delay time	$V_{DS} = 50 \text{ V}; \text{ R}_{L} = 1.1 \Omega; \text{ V}_{GS} = 10 \text{ V};$	-	23	-	ns
t <sub>r</sub>	rise time	$R_{G(ext)} = 4.7 \ \Omega; \ T_{j} = 25 \ ^{\circ}C$	-	31	-	ns
t <sub>d(off)</sub>	turn-off delay time		-	52.5	-	ns
t <sub>f</sub>	fall time		-	25	-	ns

Symbol

Source-drain diode

# **PSMN012-100YS**

Max

Unit

Тур

#### N-channel 100V 12mΩ standard level MOSFET in LFPAK

Min

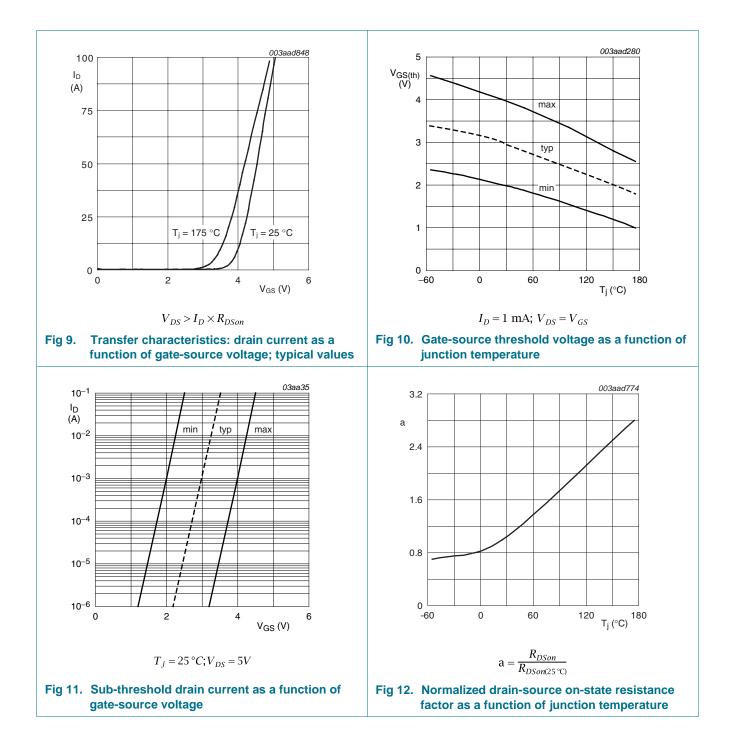
SD	source-drain voltage	$I_{S} = 15 \text{ A}, V_{GS} = 0 \text{ V}, 1$	<sub>j</sub> = 25 °C; see <u>Figure 17</u>	-	0.8	1.2	V
	reverse recovery time		A/ $\mu$ s; V <sub>GS</sub> = 0 V;	-	56	-	ns
r	recovered charge	V <sub>DS</sub> = 50 V		-	129	-	nC
		0001040				000	
12	20	003aad849	6000			003aad850	
g <sub>fs</sub> (S)			C (pF)				
9	90						
			4000				
-							
6	50					Crss	
			2000				
3	30						
	o /		0				
	0 25 50	75 <sub>I<sub>D</sub> (A)</sub> 100	0 3	6	9	V <sub>GS</sub> (V) 12	2
	$T \rightarrow C \cdot V$			1 014-6	1 1 477 -		
	$T_j = 25 ^{\circ}C; V_D$	s = 20 V		$V_{DS} = 0 V; f$			
ig 5.	Forward transconduct	$s_s = 20V$ ance as a function of	Fig 6. Input and re	everse tra	nsfer cap		
ig 5.		$s_s = 20V$ ance as a function of alues		everse tra	nsfer cap	e; typica	values
	Forward transconduct	$s_s = 20V$ ance as a function of	Fig 6. Input and re	everse trai gate-sour	nsfer cap ce voltag	e; typica	values
R <sub>DSor</sub>	Forward transconduct drain current; typical v	$s_s = 20V$ ance as a function of alues	Fig 6. Input and refunction of g	everse trai gate-sour	nsfer cap	e; typica	values
R <sub>DSor</sub> (mΩ)	Forward transconduct drain current; typical v	$s_s = 20V$ ance as a function of alues	Fig 6. Input and refunction of g	everse trai gate-sour	nsfer cap ce voltag	e; typica	values
R <sub>DSol</sub> (mΩ)	Forward transconduct drain current; typical v	$s_s = 20V$ ance as a function of alues	Fig 6. Input and refunction of g	everse trai gate-sour	nsfer cap ce voltag	e; typica	l values
R <sub>DSor</sub> (mΩ)	Forward transconduct drain current; typical v	$s_s = 20V$ ance as a function of alues	Fig 6. Input and refunction of g	everse trai gate-sour	nsfer cap ce voltag	e; typica	values
R <sub>DSol</sub> (mΩ)	Forward transconduct drain current; typical v	$s_s = 20V$ ance as a function of alues	Fig 6. Input and refunction of g	everse trai gate-sour	nsfer cap ce voltag	e; typica 003aad847 5.5 5.0	l values
R <sub>DSol</sub> (mΩ)	Forward transconduct drain current; typical v	$s_s = 20V$ ance as a function of alues	Fig 6. Input and refunction of g	everse trai gate-sour	nsfer cap ce voltag	e; typica 003aad847 5.5 5.0 4.8	l values
R <sub>DSol</sub> (mΩ)	Forward transconduct drain current; typical v	$s_s = 20V$ ance as a function of alues	Fig 6. Input and refunction of g	everse trai gate-sour	nsfer cap ce voltag	e; typica 003aad847 5.5 5.0	values
R <sub>DSoi</sub> (mΩ)	Forward transconduct drain current; typical v	$s_s = 20V$ ance as a function of alues	Fig 6. Input and refunction of g	everse trai gate-sour	0.0	e; typica 003aad847 5.5 5.0 4.8 4.5	l values
R <sub>DSoi</sub> (mΩ)	Forward transconduct drain current; typical v	$s_s = 20V$ ance as a function of alues	Fig 6. Input and refunction of g	everse trai gate-sour	0.0	e; typica 003aad847 5.5 5.0 4.8	l values
R <sub>DSol</sub> (mΩ)	Forward transconduct drain current; typical v	S = 20V ance as a function of alues 003aad852 003ai	Fig 6. Input and refunction of g	everse trai gate-sour	0.0	e; typica 003aad847 5.5 5.0 4.8 4.5	l values
R <sub>DSol</sub> (mΩ)	Forward transconduct drain current; typical v	$s_{S} = 20V$ ance as a function of alues 003aad852 003aad852 14 VGS (V) 20	Fig 6. Input and refunction of g	everse trai gate-source 1	0.0	e; typica 003aad847 5.5 5.0 4.8 4.5 / <sub>GS</sub> (V) = 4-	l values
R <sub>DSol</sub> (mΩ)	Forward transconduct drain current; typical v 40 31 22 13 4 2 4 2 3 4 4 2 3 4 2 3 4 2 3 4 2 3 4 2 3 4 2 3 4 2 3 4 2 3 4 2 3 4 2 3 4 2 3 4 2 3 4 4 2 3 3 4 2 3 3 4 2 3 3 4 4 2 3 3 4 4 2 3 3 4 4 2 3 3 4 4 2 3 3 4 4 2 3 3 4 4 2 3 3 4 4 2 3 3 4 4 2 3 3 4 4 2 3 3 3 4 3 4 3 4 3 4 4 3 4 3 4 4 3 4 3 4 4 4 3 3 4 4 4 3 3 4 4 4 3 3 4 4 4 3 3 4 4 4 3 3 4 4 4 4 3 3 4 4 4 3 3 4 4 4 3 3 4 4 4 4 3 3 4 4 4 4 3 4 4 4 4 4 4 4 4 4 4	$s_{S} = 20V$ ance as a function of alues 003aad852 003aad852 14 VGS (V) 20	Fig 6. Input and refunction of g	everse trai gate-source 1	0.0 0.0	e; typica 003aad847 5.5 5.0 4.8 4.5 V <sub>GS</sub> (V) = 4- V <sub>DS</sub> (V) <sup>2</sup>	I value:

#### Characteristics ... continued Table 6. Parameter

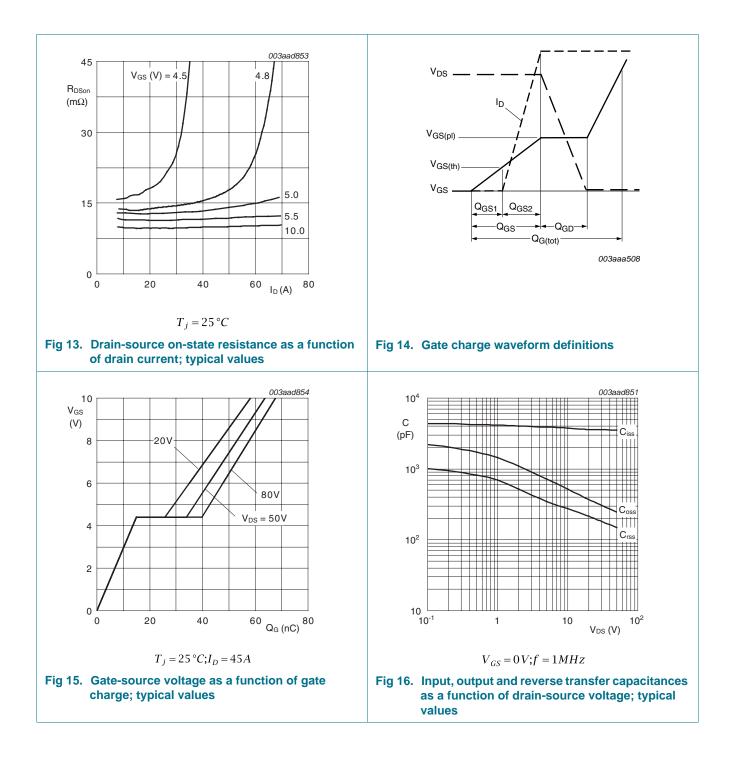
Conditions

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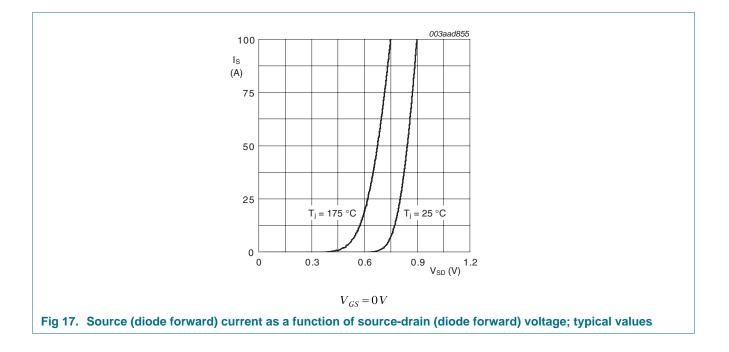
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# **PSMN012-100YS**



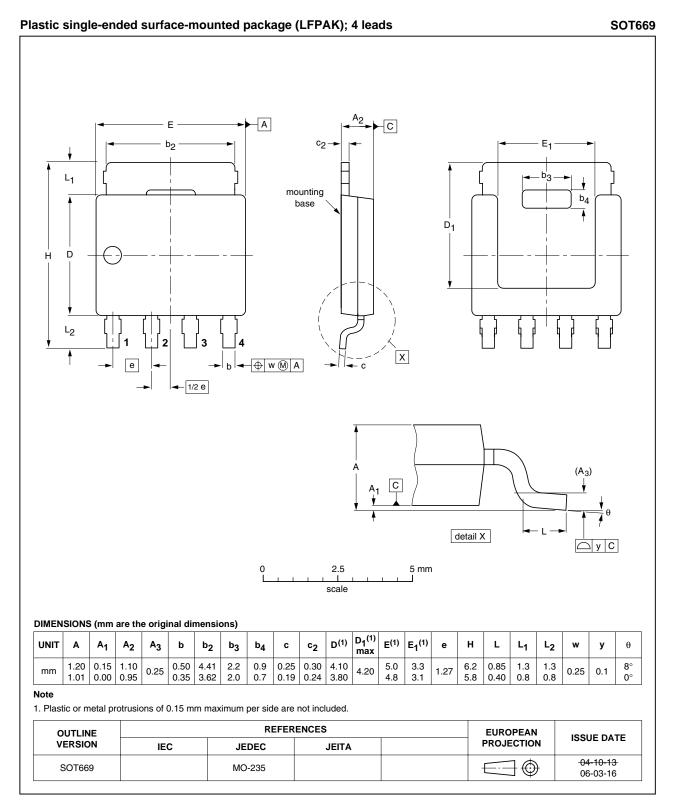
# **PSMN012-100YS**



## **PSMN012-100YS**

N-channel 100V 12m $\Omega$  standard level MOSFET in LFPAK

### 7. Package outline



#### Fig 18. Package outline SOT669 (LFPAK)

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N-channel 100V 12mΩ standard level MOSFET in LFPAK

### 8. Revision history

Table 7. Revision his	story			
Document ID	Release date	Data sheet status	Change notice	Supersedes
PSMN012-100YS_4	20100223	Product data sheet	-	PSMN012-100YS_3
Modifications:	<ul> <li>Status chai</li> </ul>	nged from objective to pro	oduct.	
PSMN012-100YS_3	20100107	Product data sheet	-	PSMN012-100YS_2
PSMN012-100YS_2	20091214	Objective data sheet	-	PSMN012-100YS_1
PSMN012-100YS_1	20091022	Objective data sheet	-	-

### 9. Legal information

#### 9.1 Data sheet status

Document status [1][2]	Product status <sup>[3]</sup>	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

[1] Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions".

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